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# United States Patent [19]

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Nightingale et al.

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## [54] ELECTRICAL TEST PROBE

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[73] Assignee: **Tektronix, Inc.**, Wilsonville, Oreg.

[\*\*] Term: **14 Years**

[21] Appl. No.: **5,220**

[22] Filed: **Feb. 26, 1993**

[52] U.S. Cl. .... **D10/78**

[58] Field of Search ..... **324/72.5, 158 P; D10/78**

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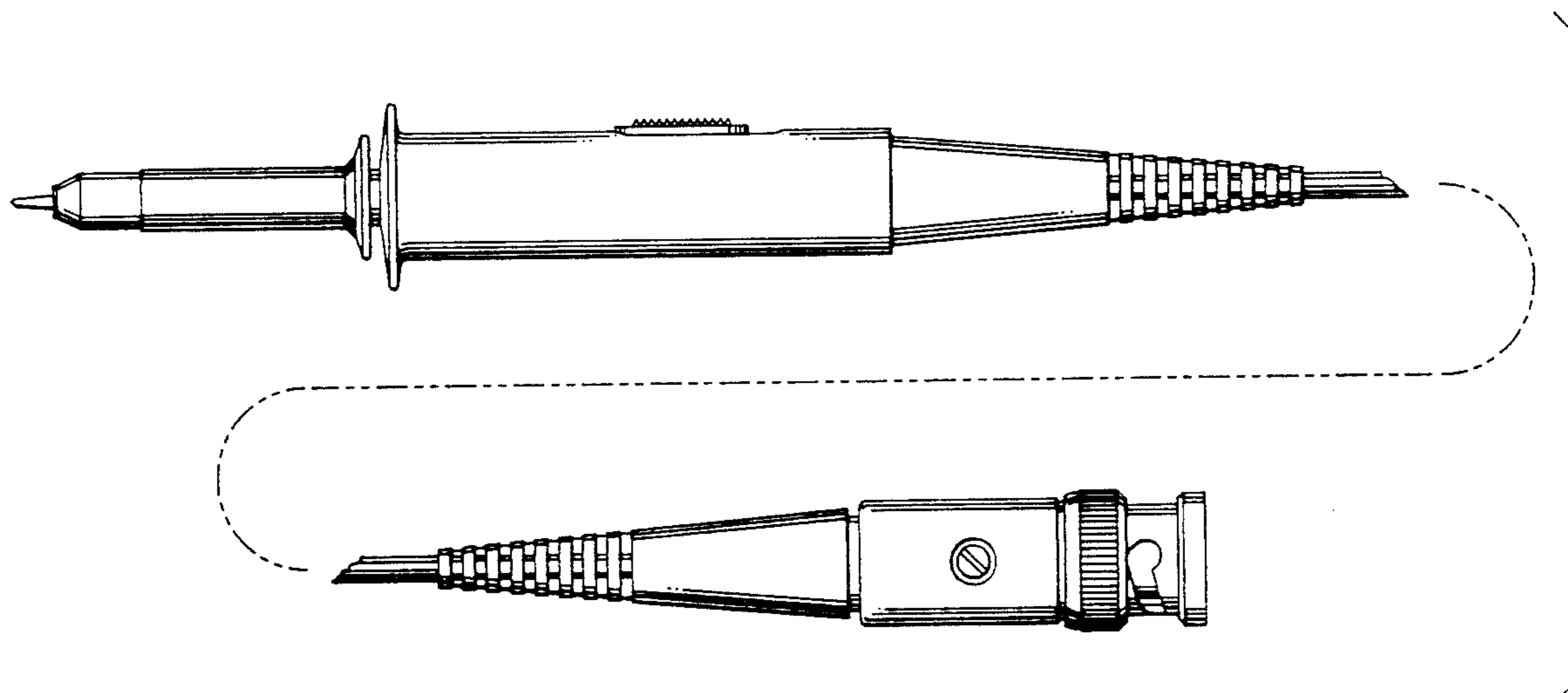
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## [57] CLAIM

The ornamental design for an electrical test probe, as shown and described.

## DESCRIPTION

FIG. 1 is a left side elevation view of the electrical test probe showing our new design; FIG. 2 is a right side elevation view thereof; FIG. 3 is a top plan view thereof; FIG. 4 is a bottom plan view thereof; FIG. 5 is a rear elevation view thereof; and, FIG. 6 is a front elevation view thereof. Portions of the cord member have been eliminated for ease of illustration.



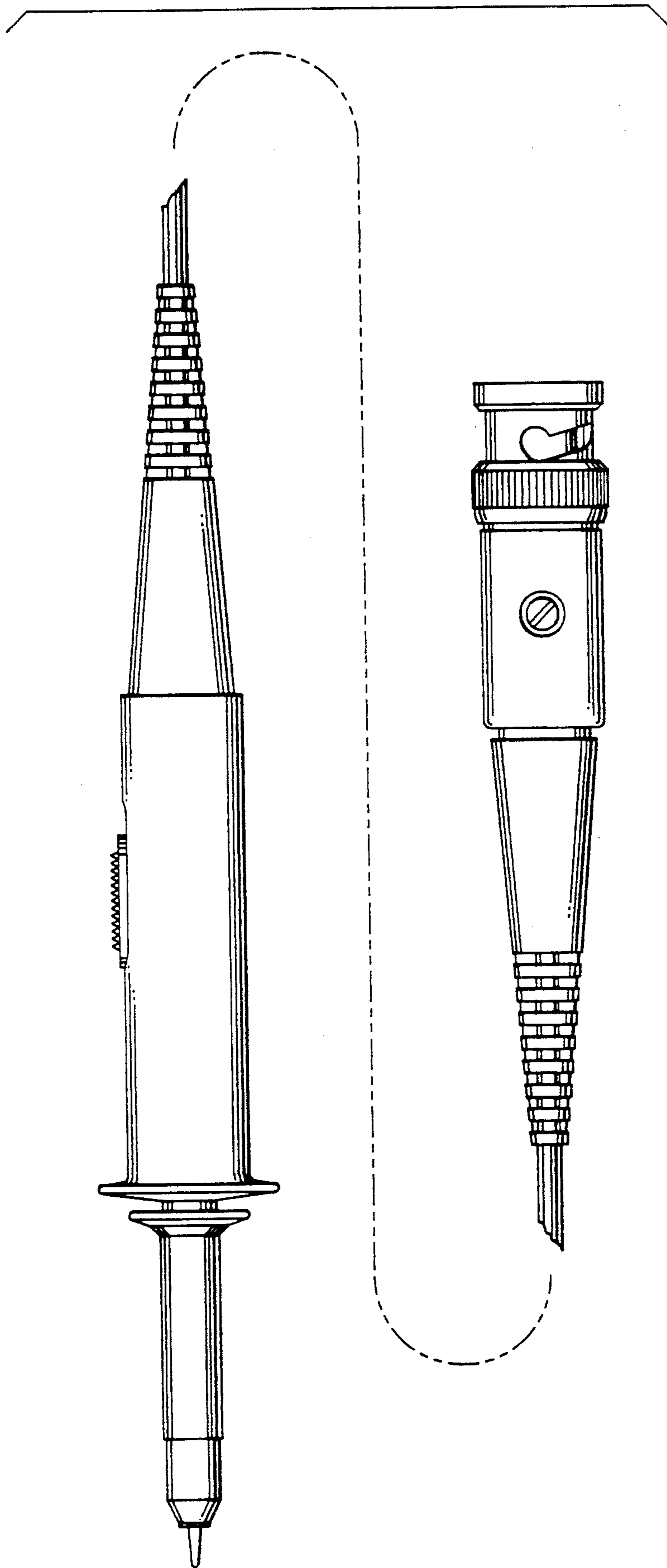


Fig. 1

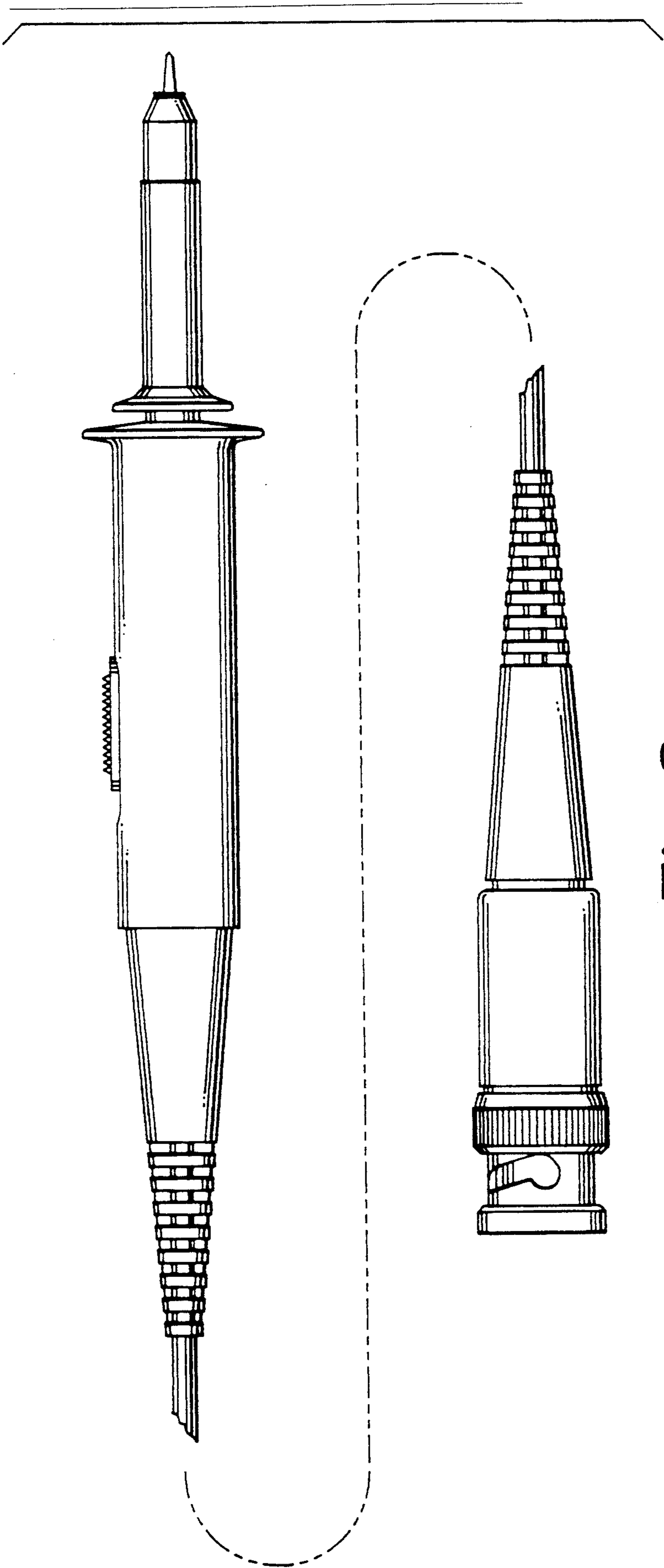


Fig. 2

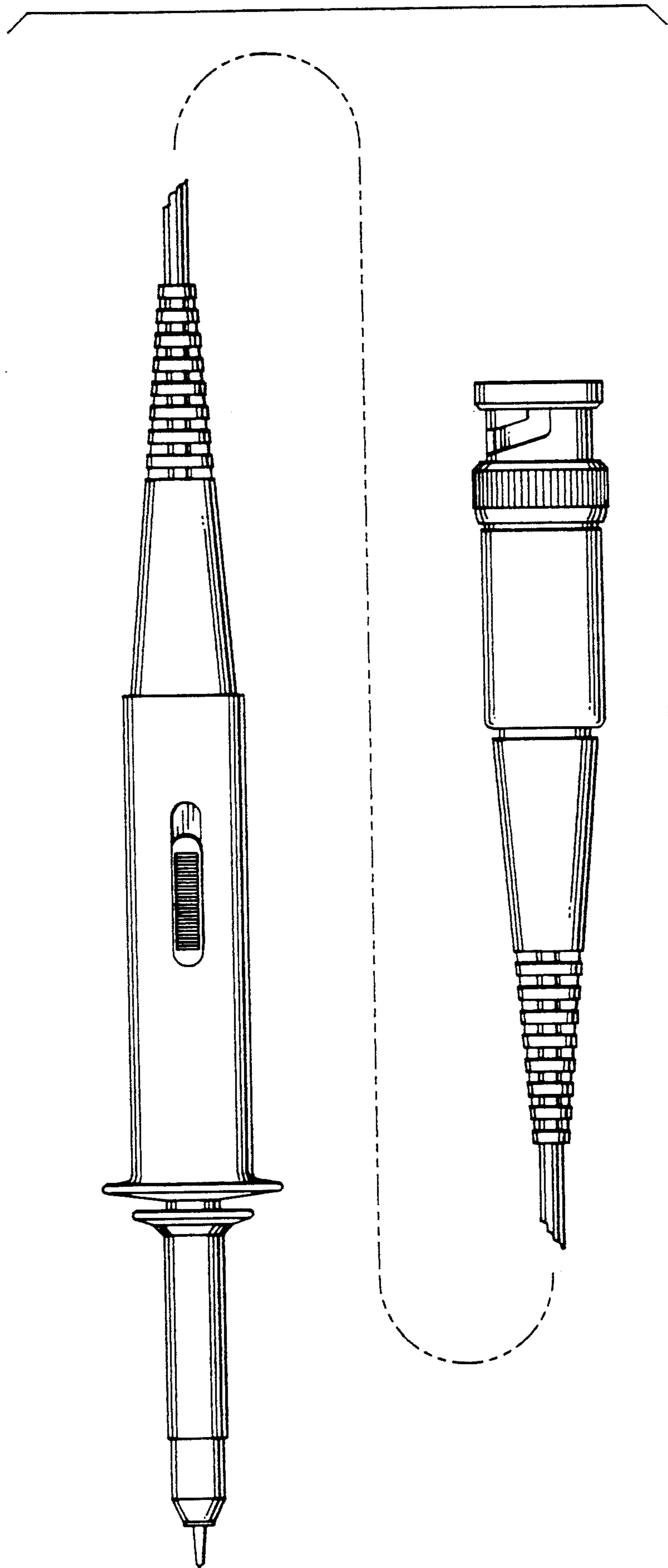


Fig. 3

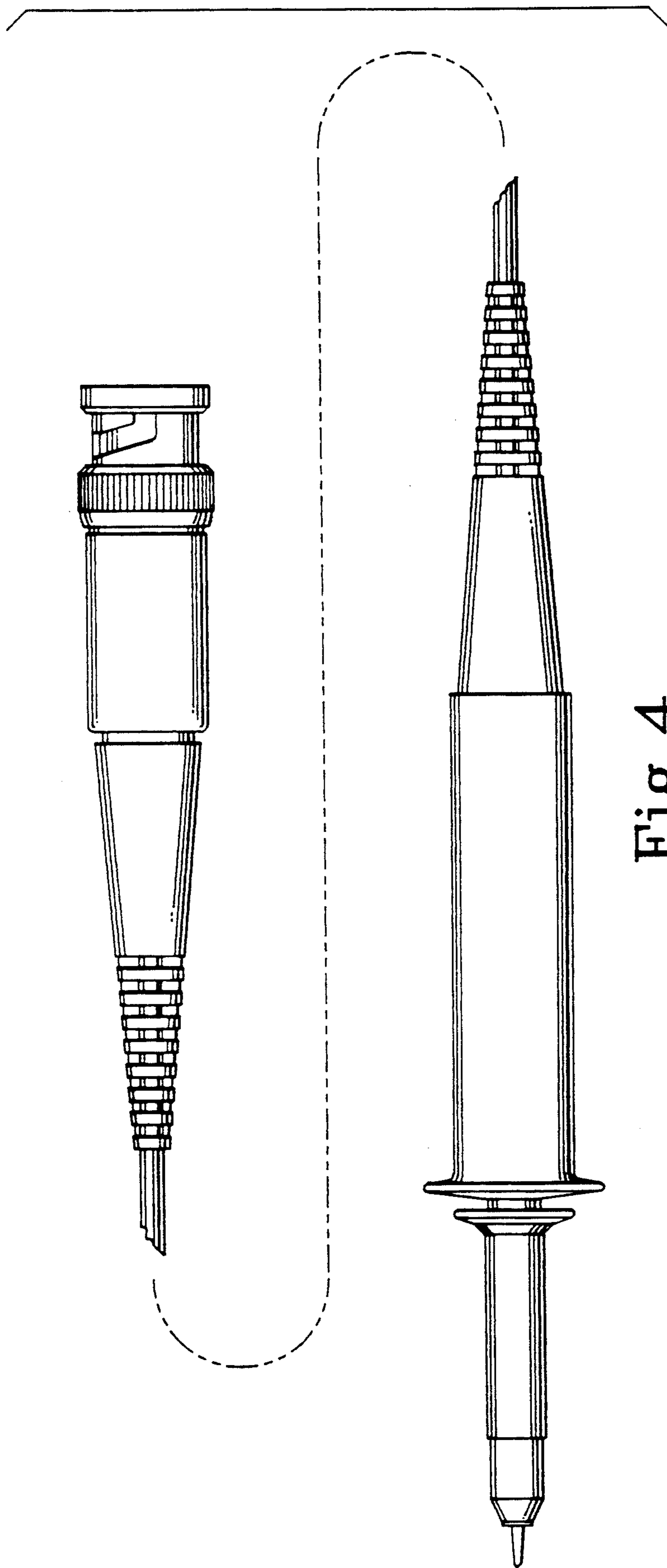


Fig. 4

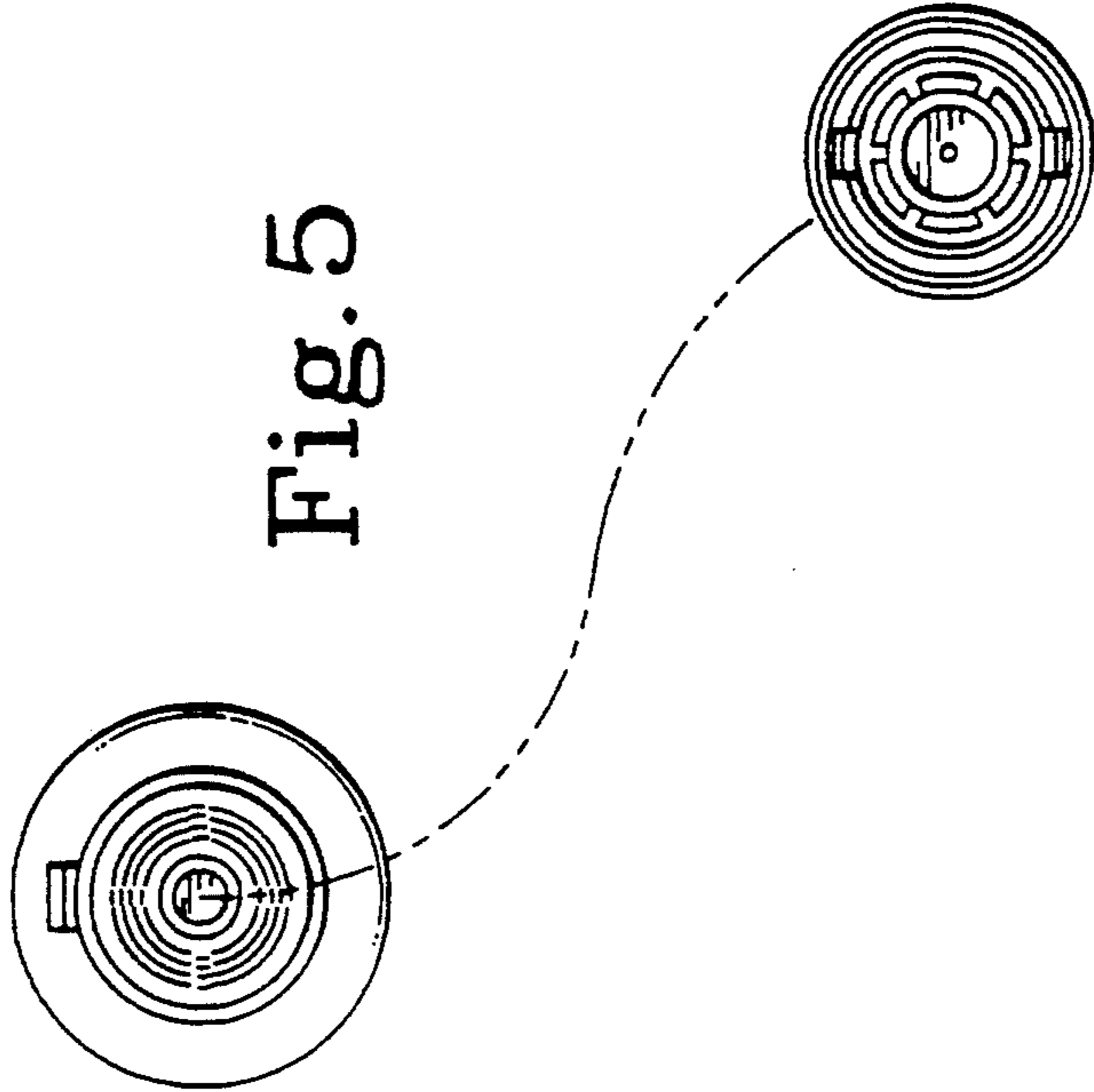


Fig. 5

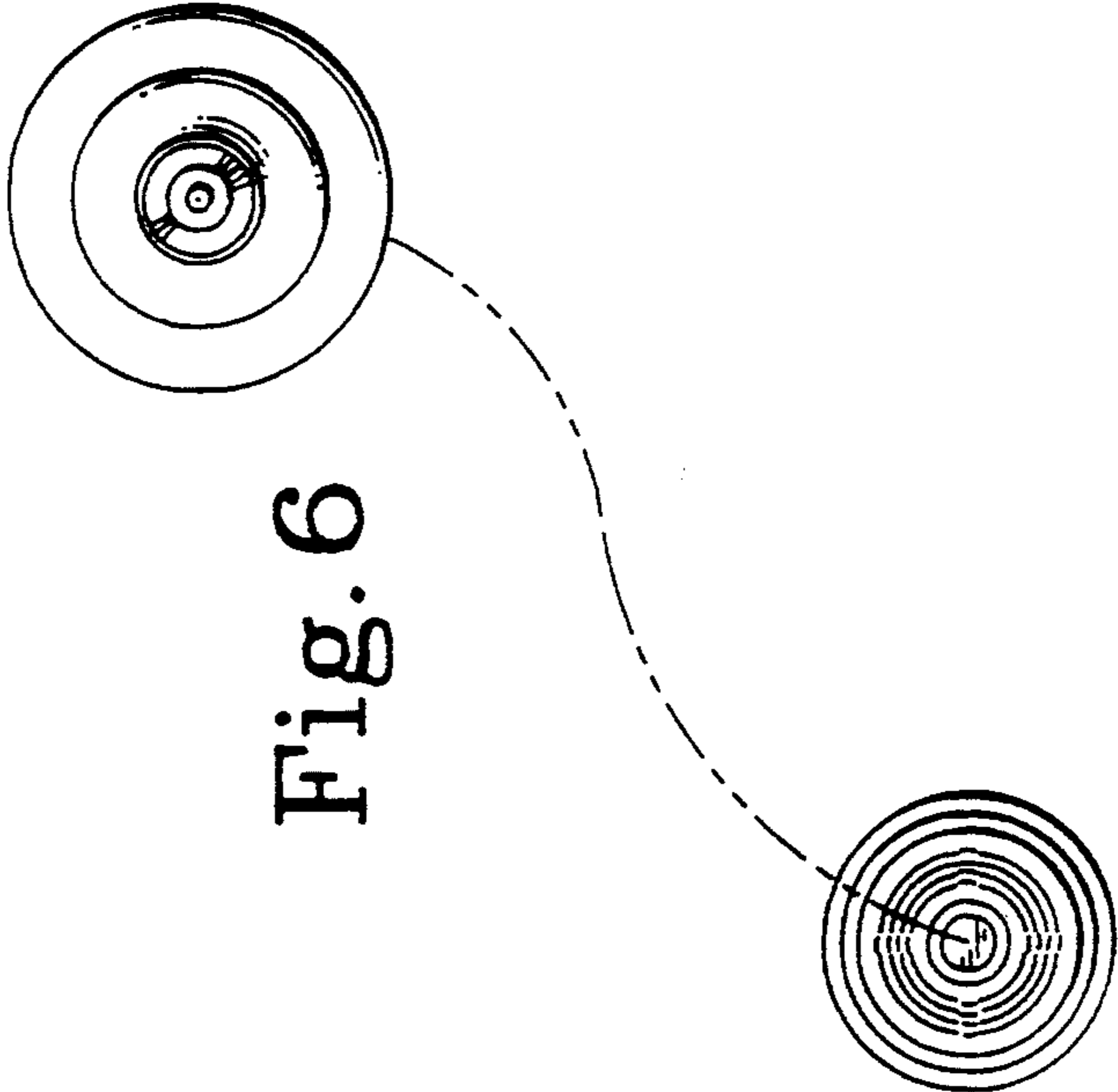


Fig. 6